

PROCEEDINGS OF SPIE

# ***Optical Technology and Measurement for Industrial Applications Conference 2022***

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**18–22 April 2022  
Yokohama, Japan**

*Published by*  
SPIE

**Volume 12480**

Proceedings of SPIE 0277-786X, V. 12480

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

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Please use the following format to cite material from these proceedings:

Author(s), "Title of Paper," in *Optical Technology and Measurement for Industrial Applications Conference 2022*, edited by Takeshi Hatsuzawa, Rainer Tutsch, Toru Yoshizawa, Proc. of SPIE 12480, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510660670

ISBN: 9781510660687 (electronic)

Published by

**SPIE**

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)

[SPIE.org](http://SPIE.org)

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